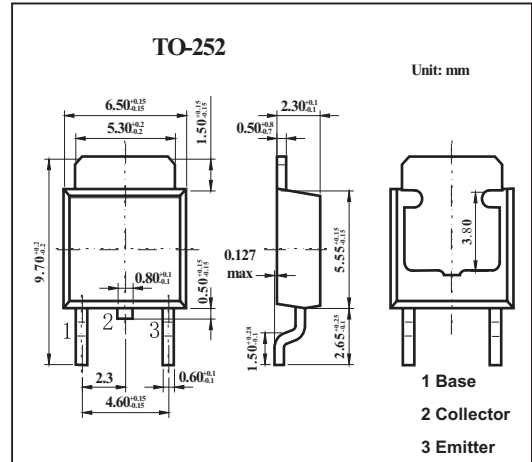


■ Features

- High voltage and large current capacity
- Adoption of MBIT process
- Fast switching time



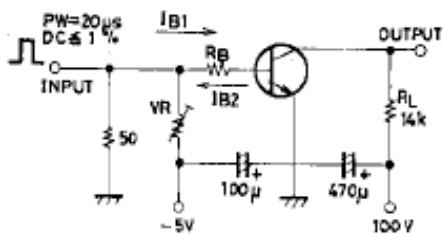
■ Absolute Maximum Ratings Ta = 25°C

Parameter	Symbol	Rating	Unit
Collector to base voltage	V _{CBO}	180	V
Collector to emitter voltage	V _{CEO}	160	V
Emitter to base voltage	V _{EBO}	6	V
Collector current (DC)	I _C	1.5	A
Collector current (Pulse)	I _{CP}	2.5	A
Total Power dissipation Ta = 25°C Tc = 25°C	P _C	1	W
		15	W
Junction temperature	T _J	150	°C
Storage temperature	T _{stg}	-55 to +150	°C

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Test conditions	Min	Typ	Max	Unit
collector cutoff current	IcBO	V _{CB} =120V, I _E =0			1.0	μA
emitter cutoff current	I _E BO	V _{EB} =4V, I _C =0			1.0	μA
DC current Gain	h _{FE}	V _{CE} =5V, I _C =100mA	100		400	
		V _{CE} =5V, I _C =10mA	80			
Gain-Bandwidth Product	f _T	V _{CE} =10V, I _C =50mA		120		MHz
Output Capacitance	C _{ob}	V _{CB} =10V, f=1MHz		12		pF
C-E Saturation Voltage	V _{CE(sat)}	I _C =50mA, I _B =50mA		0.13	0.45	V
B-E Saturation Voltage	V _{BE(sat)}	I _C =50mA, I _B =50mA		0.85	1.2	V
C-B Breakdown Voltage	V _{(BR)CBO}	I _C =10μA, I _E =0	180			V
C-E Breakdown Voltage	V _{(BR)CEO}	I _C =1mA, R _{BE} =∞	160			V
E-B Breakdown Voltage	V _{(BR)EBO}	I _E =10μA, I _C =0	6			V
Turn-ON Time	t _{on}	see specified Test Circuit		60		μs
Storage Time	t _{stg}			1.2		μs
Turn-OFF Time	t _{off}			80		μs

■ Switching Time Test Circuit



$10I_{B1} = -10I_{B2} = I_C = 0.7A$
 For PNP, the polarity is reversed.

Unit (Resistance : Ω, Capacitance : F)

■ hFE Classification

Marking	R	S	T
hFE	100 to 120	140 to 280	200 to 400